|  |  |
| --- | --- |
| **Name (PI)** |  |
| **Institution** |  |
| **Telephone:** |  |
| **Email address:** |  |
| **Date:** |  |
| **Grant No:** |  |
| **NC Sample No(s).** |  |

**Degree of Difficulty**

|  |  |  |
| --- | --- | --- |
|  | From Access Form (reflects project as a whole) Y/N | From epitaxial request (reflects this wafer structure) Y/N |
| Novel materials/combinations/processes |  |  |
| Materials/combinations/processes new to Sheffield |  |  |
| Recently developed materials |  |  |
| New applications or designs |  |  |
| Demanding thickness, doping and/or composition tolerances |  |  |
| Novel complex and difficult structures |  |  |
|  | | |
| If any, what parts of the wafer specification are tested in the user’s lab, e.g. laser wavelength, spontaneous emission, etc?  Please give details: | | |

**Quality of sample/service** (taking account of the Degree of Difficulty above)

Rating system: **1** – poor, **2** - below expectations, **3** - meets expectations, **4** – exceeds expectations

|  |  |
| --- | --- |
|  | Rating |
| Timeliness of delivery |  |
| Level and usefulness of technical advice |  |
| Receptiveness to innovation |  |
| Quality of sample with regard to the growth specification? |  |
| Communication – response time |  |
| Communication – usefulness |  |

**With regard to the aims of your project did the sample meet your requirements (your views here, are particularly important if have given a score of 1 or 2 in any of the sections above)?**

**Please enter comments below:**